

# Micro-electromechanical System Gas Sensors Based on CeO<sub>2</sub> Nanoparticles

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In this study, X-ray diffraction (XRD) analysis was used to show that cerium oxide (CeO<sub>2</sub>) nanoparticles have a face-centered cubic structure. CeO<sub>2</sub> thin films on micro-electromechanical system (MEMS) gas sensors, which are used to test their sensitivity to hydrogen (H<sub>2</sub>), were prepared by dip coating. The test power of 116 mW (~300 °C) is the power consumption of different gas concentrations. Different gases such as NH<sub>3</sub>, CO, and NO<sub>2</sub> were also tested and compared. The results showed that CeO<sub>2</sub> has a higher response at 50 ppm than at other concentrations. The structure of the CeO<sub>2</sub> material and its reaction mechanism with H<sub>2</sub> were examined and discussed.

## 1. Introduction

With industrial development, air pollution, which severely affects the environment and personal health, is becoming increasingly serious. Air quality is an important issue that cannot be ignored today. Air pollutants can be divided into outdoor and indoor emissions or formations. The most common outdoor and indoor air pollutants originate from the use of fossil fuels for industrial and residential purposes, including gaseous SO<sub>2</sub>, NO<sub>2</sub>, CO, and volatile organic compounds, as well as particulate matter, which has attracted considerable attention recently. These air pollutants are major contributors to the global disease burden.<sup>(1–4)</sup>

There is a growing interest in developing clean and sustainable energy carriers as an alternative to fossil fuels. Hydrogen gas, as a renewable and clean energy source, can prevent air pollution due to conventional fuels. However, hydrogen (H<sub>2</sub>) is a colorless and odorless gas and is flammable. It is difficult for people to detect the presence of high concentrations of H<sub>2</sub> in the environment, resulting in exposure to high-risk environments.<sup>(5–7)</sup> Therefore, developing sensitive and accurate gas sensors for H<sub>2</sub> production and storage is critical. Metal oxide semiconductors (MOSs) have been studied extensively and are the materials used for gas sensing. When a gas reacts with the MOS material, the sensor can detect the gas based on the change in resistance.<sup>(8–12)</sup> Unlike other sensing methods, this method of observing resistance

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changes has the advantages of high sensitivity, wide operating temperature range, low cost, easy fabrication, fast response, and low power consumption. Several MOS materials can sense the reaction of  $H_2$  production in gas detection. Researchers have demonstrated cerium oxide ( $CeO_2$ ), a rare-earth resource, as a promising gas-sensing material because of its large redox properties and high oxygen storage capacity.<sup>(13–15)</sup>

In this study, a micro-electromechanical system (MEMS) heating platform structure and double gun sputtering were used to prepare a  $CeO_2$  film gas sensor. After the  $CeO_2$  membrane was produced, the film composition was determined and gas detection was performed, followed by the response analysis of the  $H_2$  gas. After monitoring the sensitivity levels to  $H_2$ , the sensing sensitivity levels to other gases ( $NH_3$ ,  $CO$ , and  $NO_2$ ) were compared to evaluate the performance of the  $CeO_2$  film gas sensor.

## 2. Materials and Methods

$CeO_2$  was prepared by a step-by-step method consisting of a nanogrinding and dispersion machine process.<sup>(16,17)</sup> A schematic of the MEMS is shown in Fig. 1(a), which shows the semiconductor cavity structure, microheater, and sensing material.

The sensor uses a p-type 400- $\mu m$ -thick silicon wafer as the substrate. A 400-nm-thick Ti layer and a 50-nm-thick Au layer were deposited on top of the established pattern. In turn, the physical vapor deposition of Ti and Pt layers was carried out. A positive photoresist (PR) was used for spin coating onto the release layer. Finally, SF<sub>6</sub> plasma surface etching was performed

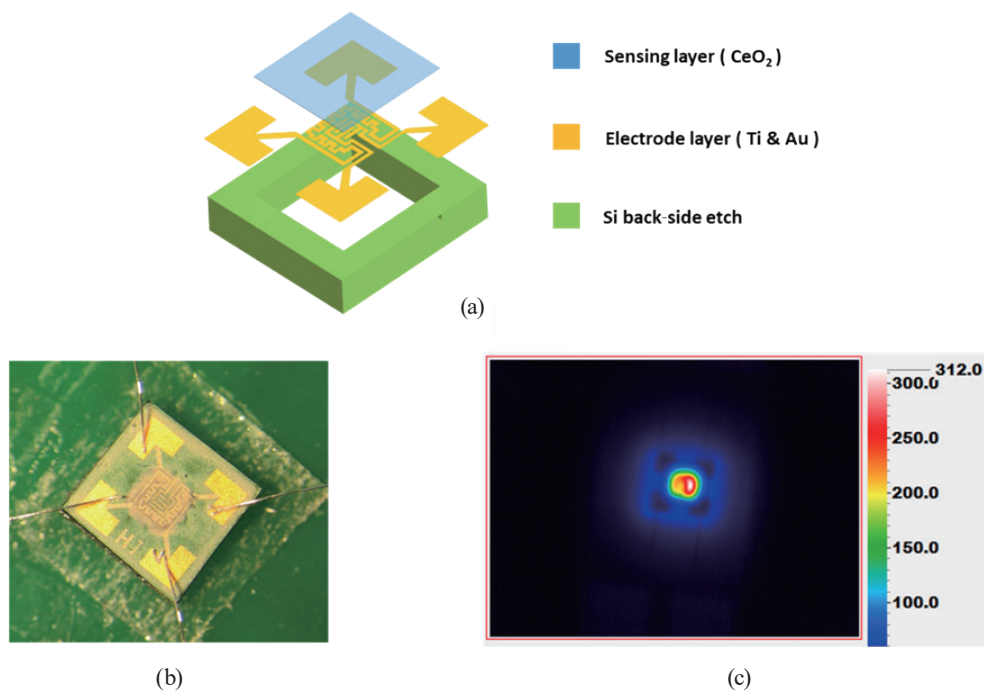


Fig. 1. (Color online) (a) Schematic of an exploded view of the gas sensor structure. (b) Top view of the sensor under a microscope. (c) Temperature distribution of sensing area under Thermal Image Camera (TIC).

to form structures on the reverse side. Microheaters work on the basis of the thermal principles of the wire. The sensing layer of CeO<sub>2</sub> was deposited by dip coating [Fig. 1(b)]. When the powers of the microheater shown in Fig. 1(c) are 28, 49, 70, 92, and 116 mW in sequence, the corresponding temperatures of the sensing film are 100, 150, 200, 250, and 300 °C, respectively. As the temperature continues to increase, the response also increases.

Gas measurements were performed in a vacuum chamber where the measured gas was inserted to record sensing parameters from the MEMS device. The MEMS microheater has four electrodes, two for sensing and two for heating. The sensing electrodes were connected to “Keithley-2400” resistance measuring equipment and the heating electrodes were connected to “MOTTECH LPS-305” for the power supply. The change in resistance as the gas entered the chamber was recorded in “lab view” software, and the obtained data were presented as graphical representations.

### 3. Results and Discussion

The crystalline structures and compositions of the samples were characterized using X-ray diffraction (XRD) (Fig. 2). The results show the XRD patterns of CeO<sub>2</sub>, which is an obvious crystal phase of cerium cubic fluorite oxide (JCPDF file no. 34–0394), and the crystal planes of fluorite phases are (111), (200), (220), (311), (222), and (400), corresponding to the peaks. The Scherrer formula [Eq. (1)] was used to calculate the full widths at half maximum for the average crystallite size. We referred to a report<sup>(18)</sup> for calculation using the main peak (111) reflection ( $2\theta = 26^\circ$ ), in which the morphological parameter or shape factor for spherical particles ( $k$ ) is 0.94 nm<sup>-1</sup>, the wavelength ( $\lambda$ ) of the radiograph is 0.154 nm, and the crystallite size of the nanostructures is 8.49 nm.

$$D = k\lambda / \cos\theta \quad (1)$$

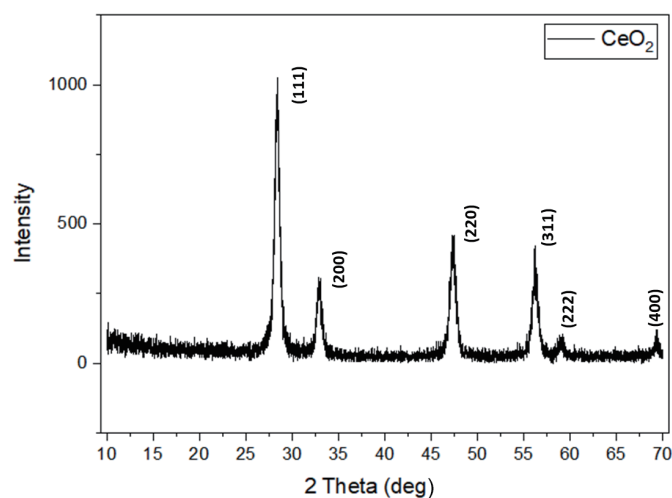


Fig. 2. XRD patterns of CeO<sub>2</sub>.

The distribution of crystallites of similar size was observed using the TEM image. The TEM image of CeO<sub>2</sub> with an inset of a select area electron diffraction (SAED) pattern is shown in Fig. 3. TEM images show that the nanocrystals have high crystallinity, there are no obvious impurities, and the CeO<sub>2</sub> nanoparticles are of different sizes. This is because some small particles combine to form large particles after being baked on the hot plate, and fine pores are generated between the particles, which benefits the gas-sensing surface area and improves the sensing sensitivity. The above results agree with previous studies.<sup>(19–21)</sup>

Gas sensing was measured in a closed cavity. After the testing gas (H<sub>2</sub> or other gases) was injected into the cavity, the sensing material of the CeO<sub>2</sub> membrane responded and decreased the resistance. When testing gas-out and air-in, the resistance increased to its original value. We recorded the change in resistance as the concentration increased from 10 to 50 ppm and the temperature ranged from 100 to 300 °C. The response was calculated as

$$Response(\%) = \frac{R_{gas} - R_{air}}{R_{gas}} \times 100\%. \quad (2)$$

Figure 4 shows the response curves of a CeO<sub>2</sub> membrane with different H<sub>2</sub> concentrations at different temperatures. The results show that the CeO<sub>2</sub> membrane has good response to H<sub>2</sub>, and the change in resistance can be measured quickly when gas-in and gas-out take place. As the H<sub>2</sub> concentration increased from 10 to 50 ppm, the response increased from 10 to 70% [Fig. 4(a)]. As the gas concentration increased, the sensing sensitivity increased significantly. Furthermore, as the temperature increased, the response speed and stability improved, with the optimal temperature being 300 °C [Fig. 4(b)–(h)]. Additionally, the sensing results were perfectly reproduced after repeated measurements, indicating that the CeO<sub>2</sub> membrane gas sensing is highly stable. We conducted sensing tests for various gases to explore the gas sensing of CeO<sub>2</sub>. The responses of the CeO<sub>2</sub> membrane with various gases (3 ppm) at 300 °C are shown in Fig. 5. The results show that the CeO<sub>2</sub> membrane has a low responses for NH<sub>3</sub>, CO, and NO<sub>2</sub>, and the obtained values are all less than 10%. That is, the CeO<sub>2</sub> membrane has high selectivity to H<sub>2</sub>.

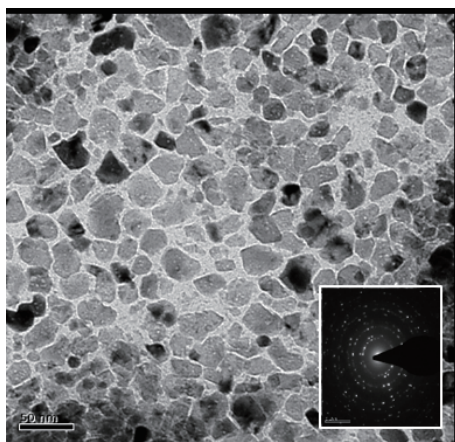


Fig. 3. TEM image of CeO<sub>2</sub>. The inset is the SAED pattern.

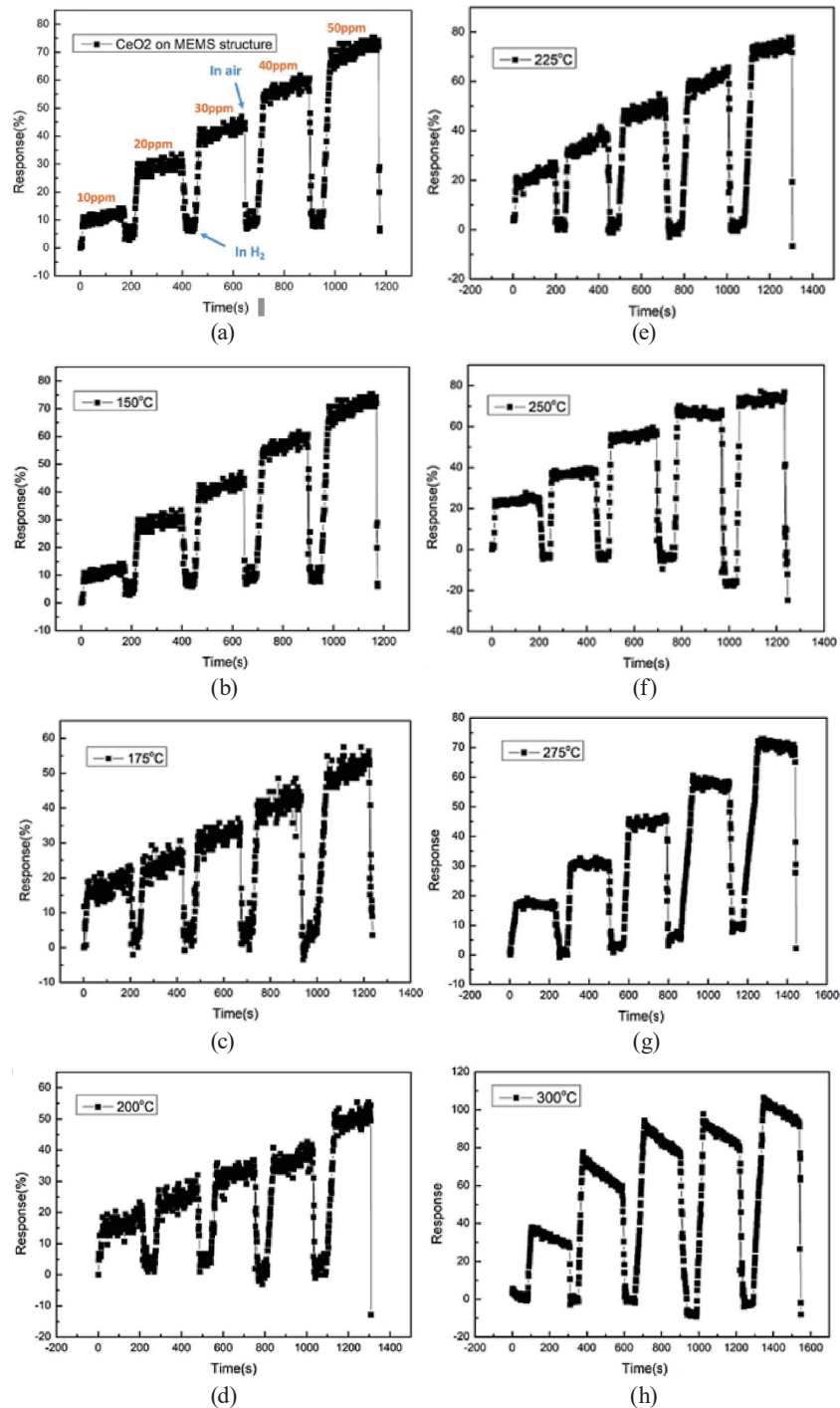


Fig. 4. (Color online) Response curves of CeO<sub>2</sub> membrane with different H<sub>2</sub> concentrations at different temperatures from 100 to 300 °C.

Figure 6 shows the sensing mechanism of a CeO<sub>2</sub> membrane at H<sub>2</sub> ambient. CeO<sub>2</sub> is an n-type MOS. When the CeO<sub>2</sub> membrane is exposed to the atmosphere, it adsorbs oxygen molecules and forms oxygen ions (O<sup>-</sup>) on the surface of the material. If H<sub>2</sub> is added to the

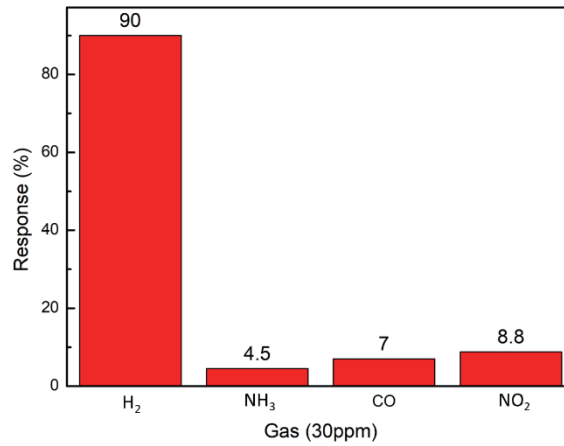


Fig. 5. (Color online) Responses of CeO<sub>2</sub> membrane with various gases (50 ppm) at 300 °C.

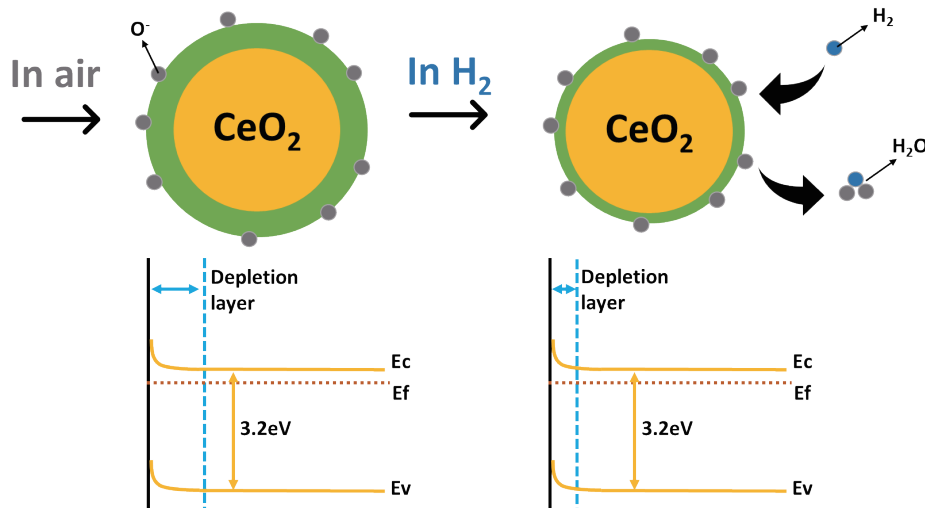


Fig. 6. (Color online) Sensing mechanism of CeO<sub>2</sub> membrane at H<sub>2</sub> ambient.

ambient atmosphere, surface O<sup>-</sup> will react with H<sub>2</sub> to form water (H<sub>2</sub>O) and electrons (e<sup>-</sup>), and the reaction is



At this point, the electron concentration in the conduction band of ceria decreases, and an electron depletion layer (EDL) is formed on the surface, increasing the resistance ( $R_{air}$ ). In this study, the exposure of CeO<sub>2</sub> to H<sub>2</sub> gas causes a reduction reaction, where the trapped electrons are released back into the conduction band and the width of the EDL decreases, resulting in a decrease in sensor resistance ( $R_{gas}$ ).<sup>(22,23)</sup>

## 4. Conclusions

In this study, the power consumption and gas concentration variables related to the sensitivity and material properties of the CeO<sub>2</sub> film were discussed. At 116 mW (~300 °C), the sensitivity increased with the H<sub>2</sub> concentration. Moreover, its sensitivity was compared with other gases. When tested at the same temperature and concentration, the maximum response of H<sub>2</sub> was 90% and those of the other three gases were less than 10%. The MEMS gas sensors of the CeO<sub>2</sub> membrane have high selectivity to H<sub>2</sub>.

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